FORM PTO 1449 (modified) "U.S. DEPARTMENT OF COMMERCE PE PATENT AND TRADEMARK OFFICE PE LIST OF REFERENCES CITED BY SPPLICANT(S) (Use several sheets if necessary) AUG 2 4 2005				ATTY DOCKET NO. 03560.003310	APPLICATION NO.	LICATION NO. 10/601,777					
				APPLICANT Tadashi Okamoto et al.							
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EDJ		5,633,495	05/27/9	7 Neihuis et al.	Neihuis et al. 250						
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EDJ	JP	60-49252	03/18/8	5 Japan	_		Abstract				
	JP	9-500486	01/14/9	7 Japan			Translation				
L	JP	7-151836	06/16/9	•			Translation				
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OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)											
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